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STGW80H65DFB, STGWT80H65DFB

Trench gate field-stop IGBT, HB series 650 V, 80 A high speed

Datasheet - production data

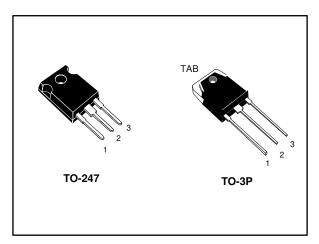
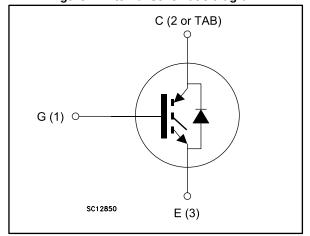


Figure 1: Internal schematic diagram



Features

- Maximum junction temperature: T_J = 175 °C
- High speed switching series
- Minimized tail current
- V_{CE(sat)} = 1.6 V(typ) @ I_C = 80 A
- Safe paralleling
- Tight parameter distribution
- Low thermal resistance
- Very fast soft recovery antiparallel diode

Applications

- Photovoltaic inverters
- High frequency converters

Description

These devices are IGBTs developed using an advanced proprietary trench gate field-stop structure. These devices are part of the new HB series of IGBTs, which represent an optimum compromise between conduction and switching loss to maximize the efficiency of any frequency converter. Furthermore, the slightly positive $V_{\text{CE(sat)}}$ temperature coefficient and very tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGW80H65DFB	GW80H65DFB	TO-247	Tube
STGWT80H65DFB	GWT80H65DFB	TO-3P	Tube

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter Value			
V _{CES}	Collector-emitter voltage (V _{GE} = 0 V)	650	V	
1-	Continuous collector current at T _C = 25 °C	120(1)	Α	
lc	Continuous collector current at T _C = 100 °C	80	A	
I _{CP} ⁽²⁾⁽³⁾	Pulsed collector current	300	Α	
V_{GE}	Gate-emitter voltage	± 20	٧	
I _F	Continuous forward current at T _C = 25 °C	120(1)	Α	
IF	Continuous forward current at T _C = 100 °C	80	A	
I _{FP} ⁽²⁾⁽³⁾	Pulsed forward current	300	Α	
Ртот	Total dissipation at T _C = 25 °C	469	W	
T _{STG}	Storage temperature range	- 55 to 150		
T_J	Operating junction temperature range	- 55 to 175	°C	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{th} JC	Thermal resistance junction-case IGBT	0.32	
R_{thJC}	Thermal resistance junction-case diode 0.66		°C/W
R _{thJA}	Thermal resistance junction-ambient 50		

⁽¹⁾Current level is limited by bond wires

 $^{^{(2)}}Pulse$ width limited by maximum junction temperature. (tp < 1ms , TJ < 175 °C)

 $[\]ensuremath{^{(3)}}\mbox{Defined}$ by design, not tested.

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)CES}	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}, I_C = 2 \text{ mA}$	650	71		V
		$V_{GE} = 15 \text{ V}, I_{C} = 80 \text{ A}$		1.6	2	
V _{CE(sat)} Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 80 A, T _J = 125 °C		1.8		V	
	voltage	V _{GE} = 15 V, I _C = 80 A, T _J = 175 °C		1.9		
		I _F = 80 A		1.9	2.3	
V _F	Forward on-voltage	I _F = 80 A, T _J = 125 °C		1.6		٧
		I _F = 80 A, T _J = 175 °C		1.5		
V _{GE(th)}	Gate threshold voltage	Vce = Vge, Ic = 1 mA	5	6	7	V
Ices	Collector cut-off current	V _{GE} = 0 V, V _{CE} = 650 V			100	μΑ
I _{GES}	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			±250	nA

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Cies	Input capacitance		-	10524	-	
Coes	Output capacitance	V _{CE} = 25 V, f = 1 MHz,	-	385	ı	рF
Cres	Reverse transfer capacitance	V _{GE} = 0 V	-	215	-	ρ.
Qg	Total gate charge	V _{CC} = 520 V, I _C = 80 A,	-	414	1	
Qge	Gate-emitter charge	V _{GE} = 15 V (see <i>Figure 29</i> :	-	78	-	nC
Qgc	Gate-collector charge	" Gate charge test circuit")	-	170	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time		-	84	-	ns
tr	Current rise time		1	52	1	ns
(di/dt) _{on}	Turn-on current slope	V _{CE} = 400 V, I _C = 80 A,	-	1270	-	A/μs
t _{d(off)}	Turn-off-delay time	$V_{GE} = 400 \text{ V}, 10 = 80 \text{ A},$ $V_{GE} = 15 \text{ V}, R_{G} = 10 \Omega$	-	280	-	ns
t _f	Current fall time	(see Figure 28: " Test circuit	-	31	-	ns
E _{on} (1)	Turn-on switching energy	for inductive load switching")	-	2.1	-	mJ
E _{off} (2)	Turn-off switching energy		-	1.5	-	mJ
Ets	Total switching energy		-	3.6	-	mJ
t _{d(on)}	Turn-on delay time		-	77	-	ns
tr	Current rise time	$V_{CE} = 400 \text{ V}, I_{C} = 80 \text{ A},$	-	51	-	ns
(di/dt) _{on}	Turn-on current slope	$V_{GE} = 15 \text{ V}, R_{G} = 10 \Omega$	-	1270	-	A/μs
t _{d(off)}	Turn-off-delay time	T _J = 175 °C	-	328	-	ns
tf	Current fall time	(see Figure 28: " Test	-	30	-	ns
Eon ⁽¹⁾	Turn-on switching energy	circuit for inductive load	-	4.4	-	mJ
E _{off} (2)	Turn-off switching energy	switching")	-	2.1	-	mJ
E _{ts}	Total switching energy		1	6.5	-	mJ

Notes:

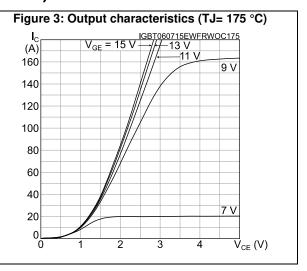
Table 7: Diode switching characteristics (inductive load)

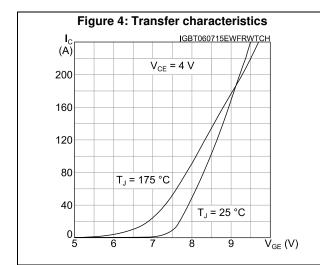
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
trr	Reverse recovery time		-	85	-	ns
Q _{rr}	Reverse recovery charge	$I_F = 80 \text{ A}, V_R = 400 \text{ V},$	-	1105	1	nC
Irrm	Reverse recovery current	di/dt = 1000 A/μs V _{GE} = 15 V,	-	26	ı	Α
dl _{rr} /dt	Peak rate of fall of reverse recovery current during tb	(see Figure 28: " Test circuit for inductive load switching")		722	1	A/μs
Err	Reverse recovery energy			267	-	μJ
t _{rr}	Reverse recovery time		-	149	ı	ns
Qrr	Reverse recovery charge	$I_F = 80 \text{ A}, V_R = 400 \text{ V},$	-	4920	ı	nC
I _{rrm}	Reverse recovery current	V _{GE} = 15 V ,T _J = 175 °C di/dt = 1000 A/µs	-	66	ı	Α
dl _{rr} /dt	Peak rate of fall of reverse recovery current during t_b	(see Figure 28: " Test circuit for inductive load switching")	-	546	1	A/μs
Err	Reverse recovery energy	3,	-	1172	-	μJ

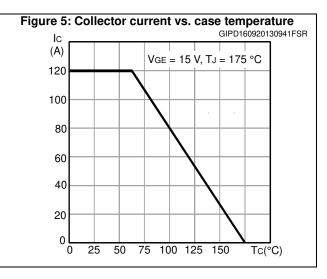
⁽¹⁾Including the reverse recovery of the diode.

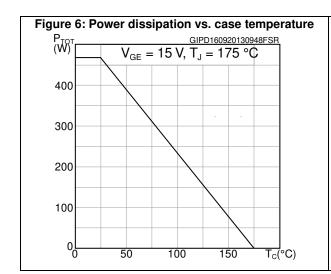
 $[\]ensuremath{^{(2)}}\mbox{Including}$ the tail of the collector current.

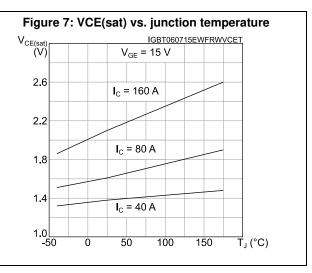
2.1 Electrical characteristics (curves)











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Figure 8: VCE (sat) vs. collector current IGBT060715EWFRWVCEC

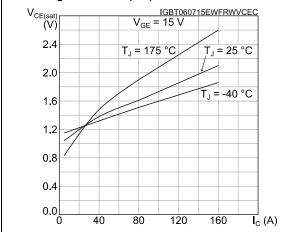


Figure 9: Forward bias safe operating area IGBT171120161002FSOA t_p = 1µs 10^{2} t_p = 10µs $t_{\rm p} = 100 \mu s$ 10¹ single pulse, $T_C = 25$ °C $T_J < 175 \,^{\circ}\text{C}, V_{GE} = 15 \,^{\circ}\text{V}$ 10^{0} $\vec{V}_{CE}(V)$ 100

Figure 10: Diode VF vs. forward current

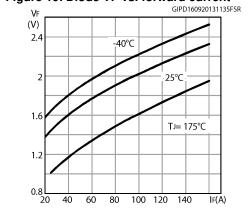


Figure 11: Normalized V(BR)CES vs. junction temperature

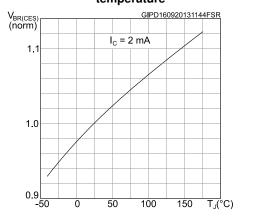


Figure 12: Normalized VGE(th) vs. junction temperature

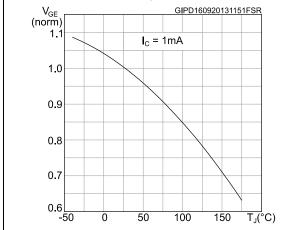


Figure 13: Gate charge vs. gate-emitter voltage

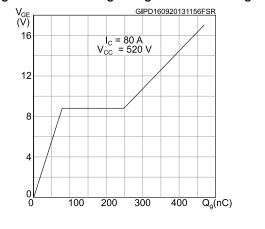
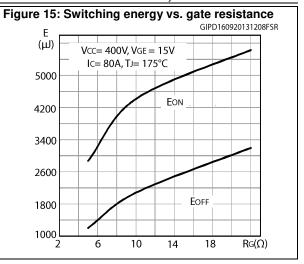
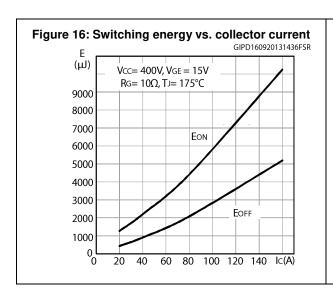
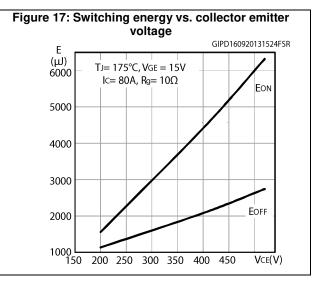
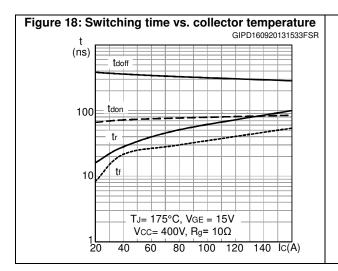


Figure 14: Switching energy vs. temperature GIPD160920131504FSR VCC = 400V, VGE = 15V4500 IC= 80A, Rg= 10Ω Eon 4000 3500 3000 2500 **E**OFF 2000 1500 1000 25 75 100 125 150 175 TJ(°C) 50









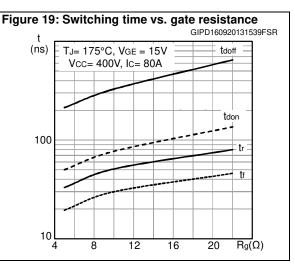
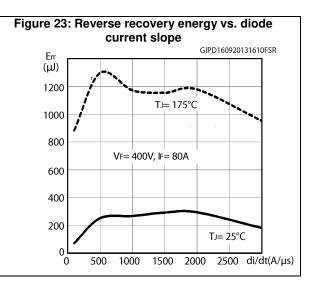
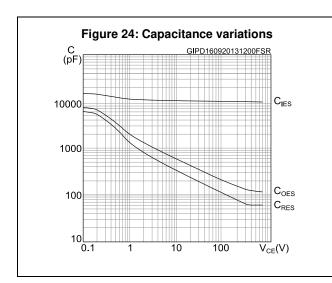


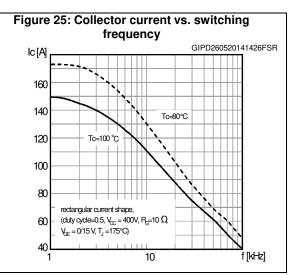
Figure 20: Reverse recovery current vs. diode current slope GIPD160920131550FSR Irm (A) VF= 400V, IF= 80A 120 TJ= 175°C 80 40 TJ= 25°C 0 2500 di/dt(A/μs) 500 1000 1500 2000

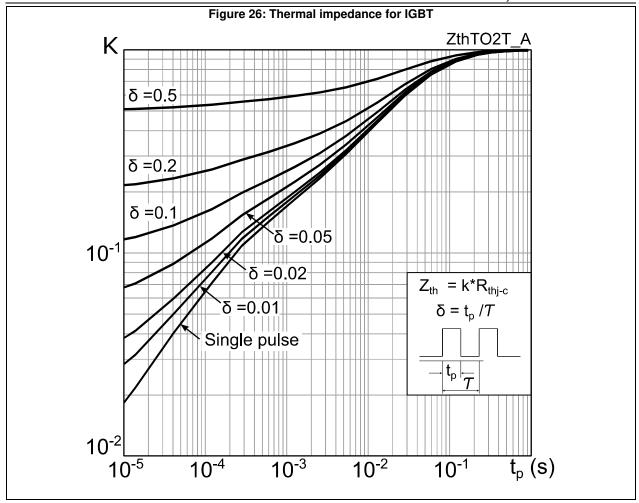
Figure 21: Reverse recovery time vs. diode current slope GIPD160920131557FSR (ns) VF= 400V, IF= 80A 350 300 250 200 TJ= 175°C 150 100 50 TJ= 25°C 1000 1500 2000 2500 di/dt(A/μs)

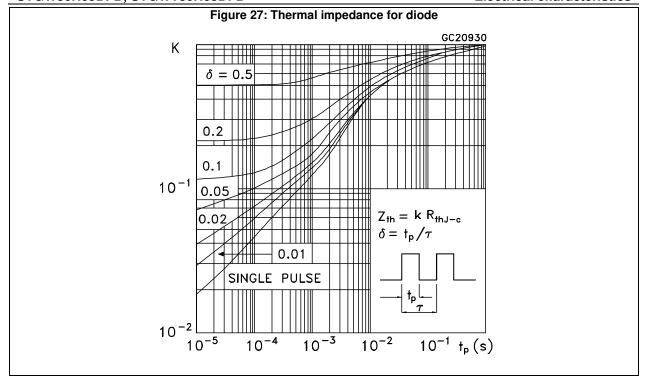
Figure 22: Reverse recovery charge vs. diode current slope GIPD160920131602FSR Qrr (nC) VF= 400V, IF= 80A 7000 TJ= 175°C 6000 5000 4000 3000 2000 1000 TJ= 25°C 2000 2500 di/dt(A/μs) 500 1000 1500 0





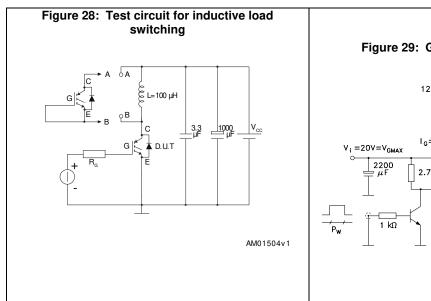


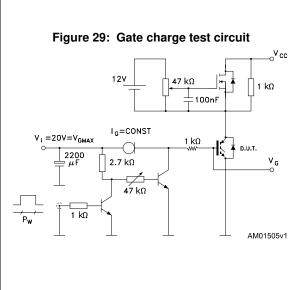


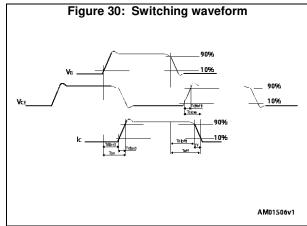


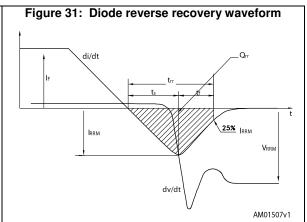
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3 Test circuits









4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-247 package information

HEAT-SINK PLANE

A

BACK VIEW

0075325,8

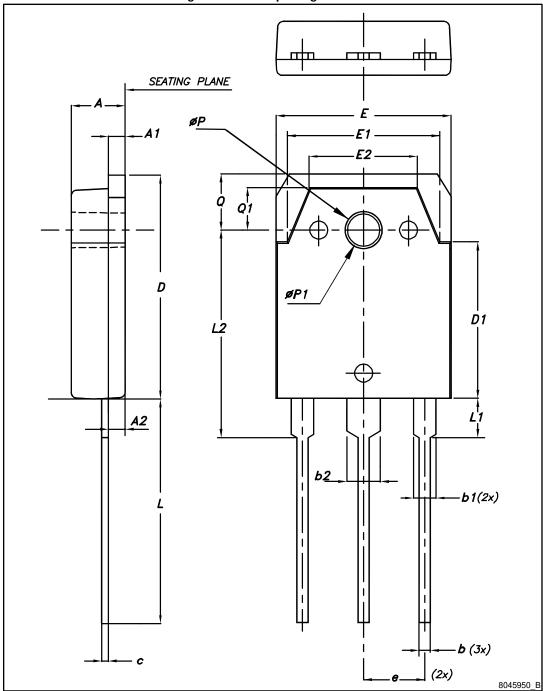
Figure 32: TO-247 package outline

Table 8: TO-247 package mechanical data

Dim	·	mm	
Dim.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

4.2 TO-3P package information

Figure 33: TO-3P package outline



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Table 9: TO-3P package mechanical data

Table 5. 10-51 package mechanical data			
Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α	4.60	4.80	5.00
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1.00	1.20
b1	1.80	2.00	2.20
b2	2.80	3.00	3.20
С	0.55	0.60	0.75
D	19.70	19.90	20.10
D1	13.70	13.90	14.10
E	15.40	15.60	15.80
E1	13.40	13.60	13.80
E2	9.40	9.60	9.90
е	5.15	5.45	5.75
L	19.80	20.00	20.20
L1	3.30	3.50	3.70
L2	18.20	18.40	18.60
ØP	3.30	3.40	3.50
ØP1	3.10	3.20	3.30
Q	4.80	5.00	5.20
Q1	3.60	3.80	4

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
12-Mar-2013	1	First release.
18-Sep-2013	2	Document status promoted from preliminary to production data. Added Section 2.1: Electrical characteristics (curves)
20-Nov-2013	3	Added device in Max247. Modified <i>Table 1</i> accordingly. Updated <i>Section 4: Package information</i> . Minor text changes in cover page.
24-Jan-2014	4	Updated title and description in cover page. Updated <i>Table 6: IGBT switching characteristics (inductive load), Table 7: Diode switching characteristics (inductive load), Figure 9: Forward bias safe operating area</i> and <i>Figure 14: Switching energy vs. temperature.</i>
13-Jun-2014	5	Updated Figure 5: Collector current vs. case temperature, Figure 6: Power dissipation vs. case temperature, Figure 18: Switching times vs. collector current, Figure 19: Switching times vs. gateresistance and Figure 24: Capacitance variations. Added Figure 25: Collector current vs. switching frequency. Updated Section 4: Package information. Minor text changes.
07-May-2015	6	Added TO-247 long leads package information.
21-Sep-2016	7	Updated Figure 2: "Output characteristics (TJ= 25 °C)", Figure 3: "Output characteristics (TJ= 175 °C)", Figure 4: "Transfer characteristics", Figure 7: "VCE(sat) vs. junction temperature" and Figure 8: "VCE (sat) vs. collector current". The part number STGY80H65DFB has been moved to a separate datasheet. Minor text changes.
17-Nov-2016	8	Updated <i>Table 2: "Absolute maximum ratings"</i> and <i>Figure 9: "Forward bias safe operating area"</i> . The part number STGWA80H65DFB has been moved to a separate datasheet. Updated document accordingly.

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